

<b>Notice of References Cited</b>	Application/Control No. 10/648,095	Applicant(s)/Patent Under Reexamination OCHIAI ET AL.
	Examiner Eric D Culbreth	Art Unit 3616

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-6,224,087 B1	05-2001	Stutz et al.	280/728.2
	C	US-2003/0094797 A1	05-2003	Sonnenberg, John	280/730.2
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**NON-PATENT DOCUMENTS**

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